

Notice of References Cited	Application/Control No. 10/582,018		Applicant(s)/Patent Under Reexamination FUJITA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,171,527	01-2001	Warino et al.	264/1.33
*	B	US-3,593,376 A	07-1971	Kisker et al.	425/346
*	C	US-3,649,144 A	03-1972	Breck, Jr., Louis William	425/136
*	D	US-3,779,684 A	12-1973	Folkes, Hugh Lorain	425/233
*	E	US-3,925,597 A	12-1975	Misiura et al.	174/102SC
*	F	US-4,018,552 A	04-1977	Prast et al.	425/407
*	G	US-4,556,378 A	12-1985	Nyfelner et al.	425/143
*	H	US-4,784,893 A	11-1988	Nishimoto et al.	428/209
*	I	US-4,854,845 A	08-1989	Couderc et al.	425/363
*	J	US-5,051,083 A	09-1991	Coluzzi, Antonio	425/174.8R
*	K	US-5,368,789 A	11-1994	Kamitakahara et al.	264/1.33
*	L	US-5,362,226 A	11-1994	Kataoka et al.	425/526
*	M	US-5,505,600 A	04-1996	Ureshino et al.	425/28.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 10280009 A	10-1998	Japan	MORIMOTO et al.	B22F 07/06
	O	JP 06272093 A	09-1994	Japan	MATSUMURA et al.	C25D 18/52
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	W	
	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,593,526 A	01-1997	Yokouchi et al.	156/89.15
*	B	US-5,676,983 A	10-1997	Bacher et al.	425/385
*	C	US-5,878,314 A	03-1999	Takaya et al.	399/302
*	D	US-5,993,189 A	11-1999	Mueller et al.	425/405.1
*	E	US-6,042,894 A	03-2000	Goto et al.	427/504
*	F	US-6,068,722 A	05-2000	Yu et al.	156/137
*	G	US-4,556,378 A	12-1985	Nyfelner et al.	425/143
*	H	US-6,165,391 A	12-2000	Vedamuttu, Paul	264/1.33
*	I	US-6,302,674 B1	10-2001	Arakawa et al.	425/192R
*	J	US-2002/0014169 A1	02-2002	Siler et al.	101/138
*	K	US-6,408,754 B1	06-2002	Siler et al.	101/401.1
*	L	US-2002/0187367 A1	12-2002	Sakaguchi, Yoshikazu	428/690
*	M	US-2002/0179449 A1	12-2002	Domeier et al.	205/67

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0006535 A1	01-2003	Hennessey et al.	264/403
*	B	US-6,635,979 B1	10-2003	Shiratori et al.	313/309
*	C	US-2003/0209711 A1	11-2003	Yang et al.	257/66
*	D	US-2004/0109915 A1	06-2004	Murata et al.	425/566
*	E	US-2004/0159863 A1	08-2004	Eldridge et al.	257/239
*	F	US-6,797,414 B2	09-2004	Sakaguchi, Yoshikazu	428/690
*	G	US-2004/0217342 A1	11-2004	Kokubo et al.	257/009
*	H	US-2004/0227263 A1	11-2004	Gorczyca et al.	264/001.33
*	I	US-6,852,420 B2	02-2005	Yamamoto et al.	428/446
*	J	US-6,864,130 B2	03-2005	Koo et al.	438/166
*	K	US-6,864,034 B2	03-2005	Nishida et al.	430/200
*	L	US-6,897,478 B2	05-2005	Koo et al.	257/59
*	M	US-2005/0247393 A1	11-2005	Misani et al.	156/123

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0188600 A1	08-2006	Inoue, Kazuo	425/542
*	B	US-7,094,048 B2	08-2006	Mishra et al.	425/407
*	C	US-7,134,879 B2	11-2006	Sugimoto et al.	439/66
*	D	US-7,156,640 B2	01-2007	Furuya et al.	425/195
*	E	US-2007/0063390 A1	03-2007	Massimo, Tormen	264/479
*	F	US-7,473,994 B2	01-2009	Hirano, Tomoyuki	257/701
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	X	

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